

**Search Notes**

Application/Control No.

10/625,789

Examiner

Seung H. Lee

Applicant(s)/Patent under  
Reexamination

FLETCHER ET AL.

Art Unit

2876

**SEARCHED**

Class	Subclass	Date	Examiner
235	436	12/7/2006	SL
340	571,673	12/7/2006	SL
235	435	12/7/2006	SL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Same as	Above	12/7/2006	SL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
235/383,385,492,493,435 (see printouts)	12/7/2006	SL
340/572.1, 568.1 (see printouts)	12/7/2006	SL
NPL	12/7/2006	SL